Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/533,237	TANAKA ET AL.
Examiner	Art Unit
Bao-Thuy L. Nguyen	1641

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SEARCHED						
Class	Subclass	Date	Examiner			
436	514, 518, 523, 524, 532, 534	11/28/2007	вти			
436	823, 824					
435	287.1		Ī			
435	287.2	V	IJ			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
EAST, NPL	11.	/28/2007	BTN	
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